

12500 TI Boulevard, MS 8640, Dallas, Texas 75243

PCN# 20121105001A

Qualification of CLARK-AT as new assembly site for affected device(s) moving from SCSAT, corresponding package change from punched RTK to sawn RGP and change of orderable part number(s)

Change Notification / Sample Request

Date: 11/20/2012 **To:** Newark PCN

Dear Customer:

The purpose of this A version is to correct errors in the 'Product Affected' section of the PCN document originally sent on 11/16/2012. Most of the new part numbers were listed instead of the current part numbers. This A version lists both the current part numbers affected by this PCN change along with the new part numbers that should be used in place of these current part numbers.

Please disregard the original PCN document and use this A version. We apologize for any confusion and inconvenience.

This is an announcement of change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. If you require samples to conduct an evaluation, please make any request within the 30 days—samples are not built ahead of the change. Please see the schedule on the following pages for availability dates. You may contact the PCN Manager or your local Field Sales Representative to acknowledge this PCN and request samples.

The changes discussed within this PCN will not take effect any earlier than **90** days from the date of this notification, unless customer agreement has been reached on an earlier implementation of the change. This notification period is per TI's standard process. Any negotiated alternative change requirements will be provided via the customer's defined process. Customers with previously negotiated, special requirements will be handled separately. Any inquiries should be directed to your local Field Sales Representative.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (PCN www admin team@list.ti.com).

Sincerely,

PCN Team SC Business Services Phone: +1(214) 480-6037 Fax: +1(214) 480-6659

20121105001A Attachment: 1

Products Affected:

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

DEVICE	CUSTOMER PART NUMBER
CC1101RTK	null
CC1101RTKR	null
CC110LRTKT	null
CC113LRTKT	null
CC115LRTKT	null

Technical details of this Product Change follow on the next page(s).

PC	PCN Number: 20121105001A PCN Date: 11/19/202						/19/2012							
Title: Qualification of CLARK-AT as new assembly site for affected device(s) moving from SCSAT and corresponding package change from punched RTK to sawn RGP														
	Customer Contact: PCN_ww_admin_team@list.ti.com Phone: +1(214)480-6037 Dept: Quality Services							Quality Services						
Proposed 1st Ship Date:			e:		02/19/2013	Estimated Sample Availabilit			y:	01	/16/2013			
Cha	Change Type:													
\boxtimes	Asse	mb	ly Site			Assembly Process				\boxtimes	Assembly	Mate	erial	S
	Desig	gn					Electrical Spec	cification			Mechanica	al Sp	ecif	ication
Test Site				Packing/Shipping/Labeling			Test Process							
☐ Wafer Bump Site ☐ Wafer Bump N			Material			Wafer Bump Process								
☐ Wafer Fab Site ☐ Wafer Fab Mat			terials			Wafer Fal	Pro	cess	5					
PCN Potails														

PCN Details

Description of Change:

The purpose of this A version is to correct errors in the 'Product Affected' section of the PCN document originally sent on 11/16/2012. Most of the new part numbers were listed instead of the current part numbers. This A version lists both the current part numbers affected by this PCN change along with the new part numbers that should be used in place of these current part numbers.

Please disregard the original PCN document and use this A version. We apologize for any confusion and inconvenience.

Texas Instruments is pleased to announce the ongoing qualification of its CLARK-AT facility as a new assembly site for 4x4 mm, 20-pin RTK VQFN packaged device(s) currently being assembled at its SCSAT subcon facility. A package change (see package mechanical drawings) and an order number change will accompany this change. The sawn RGP package is considered backwards compatible with the punched RTK package, i.e. no PCB footprint change is necessary. Please see the tables below for further details on site and associated RoHS compliant and REACH compliant bill of material changes. Packing materials (shipping boxes, tape & reels, trays, etc.) at the additional site will be consistent with materials currently in use at that added site.

	Current	Qualification
Assembly Site	SCSAT	CLARK-AT
Package Designator	RTK	RGP
Leadframe	SID#R002-2077X (NiPdAu)	4211288-0003 (NiPdAu)
Mount Compound	SID#R008-0103X	4207123-0002
Mold Compound	SID#R003-0302X	4208625-0005
Bond Wire	SID#R005-0077X 25.4 μm (1 mil Au)	4072459-0500 (0.96 mil
		Au)

Device Names / Orderables

The orderable part number will change to reflect the RGP package. Customers must convert their systems over to the new part numbers when this PCN goes into effect. The "Package Option Addendum" section in the updated datasheet as well as product information page on web will reflect these orderable device changes when they go into effect.

Package marking:

Current (RTK)

Qualification ongoing (RGP)

```
: QFN4X4-CC
                                  Y = YFAR
                                                                                         ! 0
                                                                                                                       TI = TI LETTERS
                                  M = MONTH
M = SECONDARY SITE CODE FOR STATS
                                                                                                                    YM = YEAR MONTH DATE CODE

LLLL = ASSY LOT CODE

S = ASSEMBLY SITE CODE FOR QSS 005-120
                                                                                              CC1101
  YMMLLLG
                               M - SECONDARY SITE CODE FOR STATS

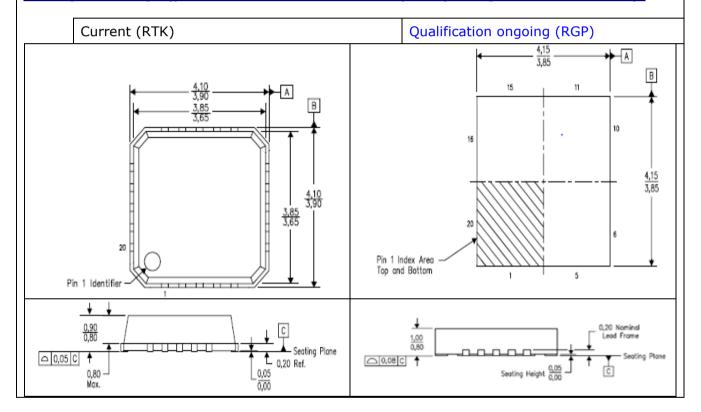
LLL = ASSY LOT CODE

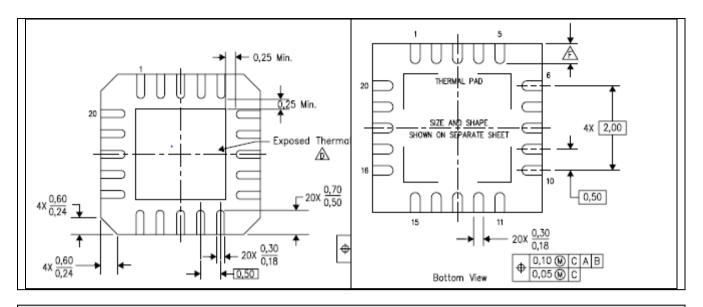
G = PRIMARY SITE CODE FOR STATS

YY = YEAR (LAST TWO DIGITS OF YEAR)

WW = WEEK NUMBER
  YYWW
                                                                                              TI YMS
                                                                                              LLLL G4
                                                                                                                        LINES 1 & 2 MAXIMUM 7 CHARACTERS PER ROW
O - PIN 1 (MARKED)
                                                                                                                               MUST BE SYMBOLIZED WITH A SOLID
                                                                                             O - PIN 1 (MARKED) G4
                                                                                                                LINE UNDERSCORE, IF PRESENT
                                 7 CHARACTERS MAX LINE 1
                                                                                                                      MUST BE SYMBOLIZED WITH AN UNDERSCORE
                                                                                         #SYMBOL ECAT : G4
                                                                                         #SYMBOL PIN 1 QUADRANT : 1
#SYMBOL DEVICE NAME1: CC1101
                                                                                         #SYMBOL DEVICE NAME2:
```

Package Drawings (please see datasheets for complete package Mechanical Data):





Reason for Change:

Continuity of Supply

Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):

Improved reliability by changing to sawn RGP package with higher package integrity.

Changes to product identification resulting from this PCN:

Shipment Labels:

Current

Assembly Site	Assembly site Origin (22L)	Assembly country Origin (23L)
SCSAT	STS	SGP
New		
Assembly Site	Assembly site Origin (22L)	Assembly country Origin (23L)
CLARK-AT	QAB	PHL

Sample product shipping label





(1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483\$I2 (P) (2P) REV: (V) 0033317 (20L) C\$0: SHE (21L) CCO:USA (22L) A\$0: MLA (23L) ACO: MY\$

Product Affected:			
Current Part number	New Part Number		
CC1100ERTKR	CC1100ERGPR		
CC1100ERTKT	CC1100ERGPT		
CC1101RTK	CC1101RGP		
CC1101RTKR	CC1101RGPR		
CC110LRTKR	CC110LRGPR		
CC110LRTKT	CC110LRGPT		
CC113LRTKR	CC113LRGPR		
CC113LRTKT	CC113LRGPT		
CC115LRTKR	CC115LRGPR		
CC115LRTKT	CC115LRGPT		
HPA00409RTKR	HPA00409RGPR		
HPA00632RTKR	HPA00632RGPR		
TLMW301RTKR	TLMW301RGPR		

Qualification Data:

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.

Qualification Schedule: Start: 2012-10-15 End: 2013-02-01

Qualification Device Construction Details:				
Device:	See the Product Affected section of this document for a list of qualified devices	<i>Qual Device1 for QBS</i> CC1101RTK		
Wafer Fab:	TSMC Fab4	TSMC Fab4		
Wafer Technology:	0.18um CMOS	0.18um CMOS		
Assembly Site:	CLARK-AT	SCS-AT		
Package Type/Code:	20VQFN / RGP	20VQFN / RTK		
Package Pins:	20	20		
Mold Compound:	4208625-0005	SID#R003-0302X		
Mold Compound Supplier:	Sumitomo	Sumitomo		
Lead Frame:	4211288-0003	SID#R002-2077X		
Composition:	NiPdAu, Cu base	NiPdAu, Cu base		
Die Attach:	4207123-0002	SID#R008-0103X		
Die Attach Supplier:	Ablestik	Ablestik		
Wire Diameter:	24.3 um (0.96 mils)	24.3 um (0.96 mils)		
Moisture Level:	MSL3	MSL3		

Qualification: Pla	n 🗌 Test Results		
Reliability Test	Conditions	Sample Size (PASS/FAIL)	
ESD HBM	Human Body Model JEDEC STD 22 A114	3 / 0 3 / 0 3 / - 3 / - PASS (QBS)	
ESD CDM	Charged Device Model JEDEC STD 22 C101	3 / 0 3 / 0 3 / - 3 / -	
Latch-up	100mA / 1.5xVddmax JEDEC STD 78	18 / 0 PASS (QBS)	
Manufacturability	Per assembly site specification	-	
Pre-conditioning Level 3	24h bake @ 125°C, 192h soak @ 30°C/60%RH, 3 IR cycles 260°C + 5/-0°C SAM required JEDEC STD 22 A113	693 / -	
Temperature Cycles air/air*	-55°C / +125°C JEDEC STD 22 A104	231 / - 231 / -	
Storage*	150°C / 600h JEDEC STD 22 A103	231 / - 231 / -	
Bias Temperature & Humidity*	130°C / 85%RH, Vmax JEDEC STD 22 A101/A110	77 / 0 PASS (QBS)	
Unbiased HAST*	110°C / 85%RH, Vmax JEDEC STD 22 A118	231 / - 231 / -	
Operating Life Test	Dynamic 140°C (480 Hrs), Vcc Max JEDEC STD 22 A108	77 / 0 PASS (QBS)	
Thermal Integrity Sequence	(level 3 @ 260C +5/-0C)	12 / - 12 / -	
Electrical characterization	Low (minimum) and high (maximum) extremes for device bias voltage and temperature.	30 units min	
Notes: * Test requires Moisture Preconditioning Qualification tests "pass" on zero fails for each test "QBS" stands for Qualification by Similarity			

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com